

Enhanced Product, Dual-Channel, 900-MHz, 2.5-nV/ $\sqrt{\text{Hz}}$, Programmable Gain Transimpedance Amplifier

1 Features

- Gain Bandwidth Product: 900 MHz
- Internal Switches for Programmable Gain
- High Impedance FET Inputs
- Input Voltage Noise 2.5 nV/ $\sqrt{\text{Hz}}$
- Slew Rate: 350 V/ μs
- Supply Voltage Range: 3.3 V to 5.25 V
- Quiescent Current: 21 mA/channel
- Power Down Mode: $I_Q < 75\mu\text{A}$
- Temperature Range: -55 °C to 125 °C
- Supports Defense, Aerospace, and Medical Applications
 - Controlled Baseline
 - One Assembly and Test Site
 - One Fabrication Site
 - Extended Product Life Cycle
 - Extended Product-Change Notification
 - Product Traceability

2 Applications

- Switchable Transimpedance Amplifier
- Smart Munitions
- [Laser Distance Measurement](#)
- [Optical Time Domain Reflectometry \(OTDR\)](#)
- Silicon Photomultiplier (SiPM) Buffer
- Photomultiplier Tube Post Amplifier
- High Speed Programmable Gain Amplifier

3 Description

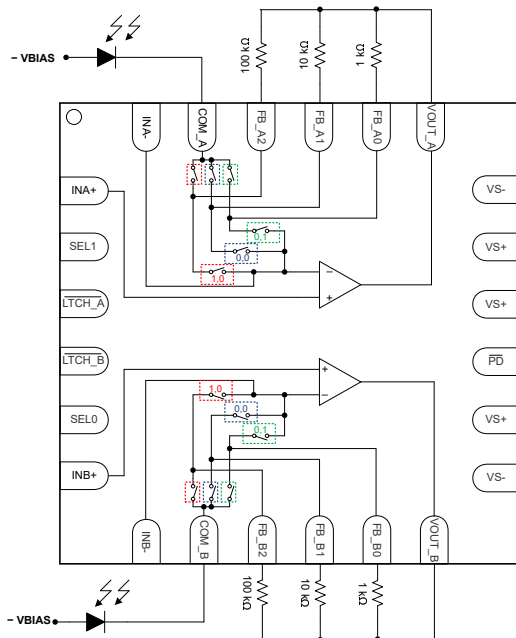
The OPA3S2859-EP is a wideband, low-noise programmable gain amplifier with CMOS inputs for wideband transimpedance and voltage amplifier applications. When the device is configured as a transimpedance amplifier (TIA), the 0.9-GHz gain bandwidth product (GBWP) enables high closed-loop bandwidths in low-capacitance photodiode (PD) applications.

The three internal switched feedback paths along with an optional parallel non-switched feedback path allows for up to four selectable gain configurations. The internal switches minimize parasitic contributions to increase performance compared to systems that use discrete external switches. Each switch is optimized for feedback resistor values ranging from $< 1 \text{ k}\Omega$ to $> 100 \text{ k}\Omega$ for wide dynamic range applications. The selected switch path is controlled for both channels using a 2-wire parallel interface. For each channel selected, the gain path can also be held constant by exerting the latch pin, which subsequently disables switch control for the selected channel and prevents the channel from changing gain.

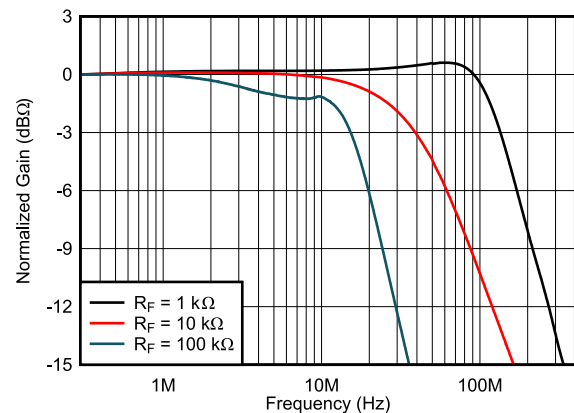
Device Information⁽¹⁾

PART NUMBER	PACKAGE	BODY SIZE (NOM)
OPA3S2859-EP	WQFN (24)	4.00 mm × 4.00 mm

- (1) See the package option addendum at the end of the data sheet for all available packages.



Block Diagram



Transimpedance Bandwidth vs Frequency



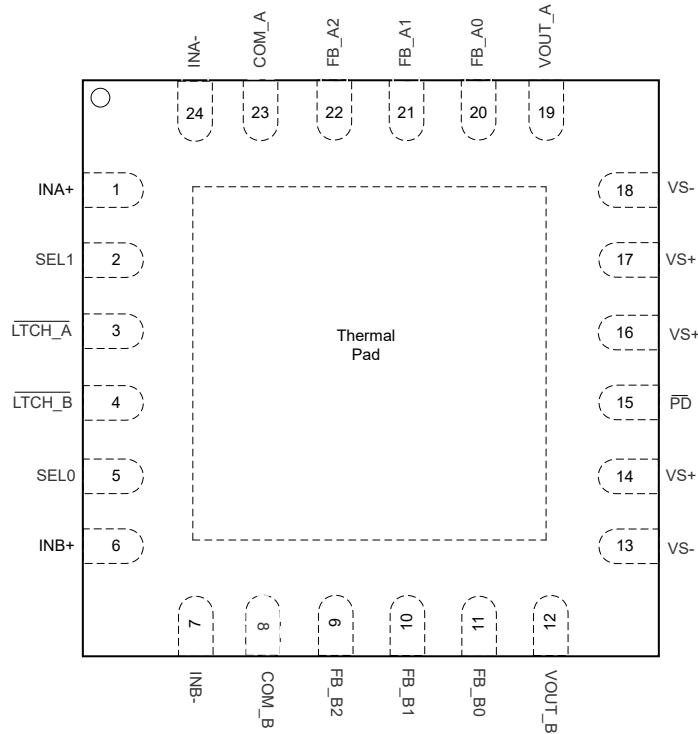
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4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

5 Pin Configuration and Functions



**Figure 5-1. RTW Package
24-Pin WQFN With Exposed Thermal Pad
Top View**

Table 5-1. Pin Functions

PIN		I/O	DESCRIPTION
NAME	NO.		
COM_A	23	I	APD input – Channel A
COM_B	8	I	APD input – Channel B
FB_A0	20	I	Feedback connection to Channel A – TIA Gain Resistor (Low gain, optimized for gain in < 10 kΩ range)
FB_A1	21	I	Feedback connection to Channel A – TIA Gain Resistor (Mid gain, optimized for gain in 10 kΩ – 100 kΩ range)
FB_A2	22	I	Feedback connection to Channel A – TIA Gain Resistor (High gain, optimized for gain in > 100 kΩ range)
FB_B0	11	I	Feedback connection to Channel B – TIA Gain Resistor (Low gain, optimized for gain in < 10 kΩ range)
FB_B1	10	I	Feedback connection to Channel B – TIA Gain Resistor (Mid gain, optimized for gain in 10 kΩ – 100 kΩ range)
FB_B2	9	I	Feedback connection to Channel B – TIA Gain Resistor (High gain, optimized for gain in > 100 kΩ range)
INA-	24	I	Negative (inverting) input for amplifier A
INA+	1	I	Positive (noninverting) input for amplifier A
INB-	7	I	Negative (inverting) input for amplifier B
INB+	6	I	Positive (noninverting) input for amplifier B

Table 5-1. Pin Functions (continued)

PIN		I/O	DESCRIPTION
NAME	NO.		
LTCH_A	3	I	Latch control input for Channel A. LTCH_A = logic high (default) = transparent mode, gain setting changes based on SEL0 and SEL1 pins are reflected at the output. LTCH_A = logic low = latch mode = changing SEL0 and SEL1 pins does not affect the gain configuration of amplifier.
LTCH_B	4	I	Latch control input for Channel B. LTCH_B = logic high (default) = transparent mode, gain setting changes based on SEL0 and SEL1 pins are reflected at the output. LTCH_B = logic low = latch mode = changing SEL0 and SEL1 pins does not affect the gain configuration of amplifier.
PD	15	I	Power down pin. PD = logic high (default) = normal operation, PD = logic low = power down mode.
SEL0	5	I	TIA gain selection. SEL0 = logic high (default). See Table 5-2 for details.
SEL1	2	I	TIA gain selection. SEL1 = logic high (default). See Table 5-2 for details.
VOUT_A	19	O	Output of amplifier A
VOUT_B	12	O	Output of amplifier B
VS-	13, 18	I	Negative (lowest) power supply
VS+	14, 16, 17	I	Positive (highest) power supply
Thermal pad		—	Connect the thermal pad to the most negative power supply (pin 13 and 18) of the device under test (DUT).

Table 5-2. Select Pin Decoder

SEL1	SEL0	Gain
LOW	HIGH	Low Gain, optimized for gain in < 10 kΩ range
LOW	LOW	Mid Gain, optimized for gain in 10 kΩ –100 kΩ range
HIGH	LOW	High Gain, optimized for gain in > 100 kΩ range
HIGH (Default)	HIGH (Default)	External Gain. All internal switches open

6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

		MIN	MAX	UNIT
V _S	Total supply voltage (V _{S+} - V _{S-})		5.5	V
V _{IN+} , V _{IN-}	Input voltage	(V _{S-}) - 0.5	(V _{S+}) + 0.5	V
V _{ID}	Differential input voltage		1	V
V _{OUT}	Output voltage	(V _{S-}) - 0.5	(V _{S+}) + 0.5	V
I _{IN}	Continuous input current		±4	mA
I _{OUT}	Continuous output current ⁽²⁾		25	mA
T _J	Junction temperature		150	°C
T _A	Operating free-air temperature	-55	125	°C
T _{stg}	Storage temperature	-65	150	°C

- (1) Stresses beyond those listed under *Absolute Maximum Rating* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Condition*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) Long-term continuous output current for electromigration limits

6.2 ESD Ratings

			VALUE	UNIT
V _(ESD)	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins ⁽¹⁾	±1000	V
		Charged device model (CDM), per JEDEC specification JESD22-C101, all pins ⁽²⁾	±500	

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
V _S	Total supply voltage (V _{S+} - V _{S-})	3.3	5	5.25	V
T _A	Ambient temperature	-55		125	°C

6.4 Thermal Information

THERMAL METRIC ⁽¹⁾		OPA3S2859-EP		
		RTW		UNIT
		24 PINS		
R _{θJA}	Junction-to-ambient thermal resistance	54.1		°C/W
R _{θJC(top)}	Junction-to-case (top) thermal resistance	55.6		°C/W
R _{θJB}	Junction-to-board thermal resistance	30.6		°C/W
Ψ _{JT}	Junction-to-top characterization parameter	2.5		°C/W
Ψ _{JB}	Junction-to-board characterization parameter	30.6		°C/W
R _{θJC(bot)}	Junction-to-case (bottom) thermal resistance	13.9		°C/W

- (1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

6.5 Electrical Characteristics

$V_{S+} = 5\text{ V}$, $V_{S-} = 0\text{ V}$, $R_L = 200\ \Omega$, output load is referenced to midsupply, input common-mode biased at midsupply, and $T_A \approx +25^\circ\text{C}$ (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
AC PERFORMANCE						
SSBW	Small-signal transimpedance bandwidth ⁽¹⁾	$V_{OUT} = 100\text{ mV}_{PP}$, Gain = 1 k Ω , $C_{IN} = 4\text{ pF}$		130		MHz
		$V_{OUT} = 100\text{ mV}_{PP}$, Gain = 10 k Ω , $C_{IN} = 4\text{ pF}$		40		MHz
		$V_{OUT} = 100\text{ mV}_{PP}$, Gain = 100 k Ω , $C_{IN} = 4\text{ pF}$		14		MHz
GBWP	Gain-bandwidth product			900		MHz
	Slew rate (10% - 90%)	$V_{OUT} = 2\text{-V step}$		350		V/ μs
e_n	Input-referred voltage noise	$f = 1\text{ MHz}$		2.5		nV/ $\sqrt{\text{Hz}}$
Z_{OUT}	Closed-loop output impedance	$f = 1\text{ MHz}$		0.1		Ω
DC PERFORMANCE						
A_{OL}	Open-loop voltage gain	$f = \text{DC}$	60	76		dB
V_{OS}	Input offset voltage	$T_A = 25^\circ\text{C}$	-8	± 0.9	8	mV
$\Delta V_{OS}/\Delta T$	Input offset voltage drift	$T_A = -55^\circ\text{C to } +125^\circ\text{C}$		-2		$\mu\text{V}/^\circ\text{C}$
I_{BN} , I_{BI}	Input bias current	$T_A = 25^\circ\text{C}$, All switches open	-50		50	pA
I_{BOS}	Input offset current	$T_A = 25^\circ\text{C}$, All switches open		35		pA
CMRR	Common-mode rejection ratio	$V_{CM} = \pm 0.5\text{ V}$ (from midsupply)	67	78		dB
INPUTS						
C_{IN+}	Non-inverting input capacitance			1.4		pF
C_{IN-}	Inverting input capacitance ⁽²⁾			3		pF
V_{IH}	Common-mode input range (high)	CMRR > 64 dB	3.4	3.6		V
		CMRR > 64 dB, $T_A = -55^\circ\text{C to } +125^\circ\text{C}$		3.4		
		CMRR > 64 dB, $V_{S+} = 3.3\text{ V}$	1.7	1.9		
V_{IL}	Common-mode input range (low)	CMRR > 64 dB		0	0.4	V
		CMRR > 64 dB, $T_A = -55^\circ\text{C to } +125^\circ\text{C}$		0.35		
		CMRR > 64 dB, $V_{S+} = 3.3\text{ V}$		0	0.4	
OUTPUTS						
V_{OH}	Output voltage (high)	$T_A = 25^\circ\text{C}$	3.95	4.1		V
		$T_A = -55^\circ\text{C to } +125^\circ\text{C}$		3.9		
		$V_{S+} = 3.3\text{ V}$, $T_A = 25^\circ\text{C}$	2.3	2.4		
V_{OL}	Output voltage (low)	$T_A = 25^\circ\text{C}$		1.1	1.15	V
		$T_A = -55^\circ\text{C to } +125^\circ\text{C}$		1.2		
		$V_{S+} = 3.3\text{ V}$, $T_A = 25^\circ\text{C}$		1.05	1.15	
I_{O_LIN}	Linear output drive (source and sink)	$R_L = 10\ \Omega$, $A_{OL} > 52\text{ dB}$	65	74		mA
		$R_L = 10\ \Omega$, $A_{OL} > 52\text{ dB}$, $T_A = -55^\circ\text{C to } +125^\circ\text{C}$		64		
I_{SC}	Output short-circuit current		90	110		mA
CHANNEL-TO-CHANNEL MATCHING						
	Crosstalk (output-referred)	$f = 1\text{ MHz}$, Gain = 100 k Ω , $V_{OUT} = 100\text{ mV}_{PP}$		-77		dB
	Offset voltage mismatch			± 1		mV
	Offset current mismatch			± 40		pA
POWER SUPPLY						
I_Q	Quiescent current	$V_{S+} = 5\text{ V}$		42		mA
		$V_{S+} = 5\text{ V}$, $T_A = +125^\circ\text{C}$		50		mA
		$V_{S+} = 5\text{ V}$, $T_A = -55^\circ\text{C}$		35		mA

6.5 Electrical Characteristics (continued)

$V_{S+} = 5\text{ V}$, $V_{S-} = 0\text{ V}$, $R_L = 200\ \Omega$, output load is referenced to midsupply, input common-mode biased at midsupply, and $T_A \approx +25^\circ\text{C}$ (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
PSRR+	Power Supply Rejection Ratio	f = DC	66	72		dB
PSRR-		f = DC	64	72		
POWER DOWN						
	Disable voltage threshold	Voltage referenced to V_{S+} , amplifier OFF below this voltage	$V_{S+} - 1.5$	$V_{S+} - 1.3$		V
	Enable voltage threshold	Voltage referenced to V_{S+} , amplifier ON above this voltage		$V_{S+} - 1.2$	$V_{S+} - 1$	V
	Power-down quiescent current			75	140	μA
	$\overline{\text{PD}}$ bias current	$V_{\text{PD}} = V_{S-}$ or V_{S+}		10		μA
		V_{PD} at switching threshold			160	
	Turnon-time delay	Time to $V_{\text{OUT}} = 90\%$ of final value		88		ns
	Turnoff time delay	Time to $V_{\text{OUT}} = 10\%$ of final value		300		ns

- (1) C_{IN} = Photodiode capacitance + PCB capacitance. Photodiode capacitance is 3.3 pF and estimated PCB capacitance is 0.7 pF.
- (2) C_{IN} refers to the capacitance at the inverting input of the amplifier. $C_{\text{IN}} = C_{\text{IN-(CM)}} + C_{\text{DIFF}}$ + Switch capacitance on the amplifier inverting pin (ON capacitance of the closed switch + OFF capacitance for open switches).

6.6 Switching Characteristics

$V_{S+} = 5\text{ V}$, $V_{S-} = 0\text{ V}$, input common-mode biased at midsupply, $R_{F0} = 1\text{ k}\Omega$, $R_{F1} = 10\text{ k}\Omega$, $R_{F2} = 100\text{ k}\Omega$, $R_L = 200\text{ }\Omega$, output load is referenced to midsupply, and $T_A \approx +25^\circ\text{C}$ (unless otherwise noted), [See schematic here.](#) (1) (2)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
GAIN SWITCHES						
	Switch transition-time (5)	SW_0 OFF to SW_1 ON		160		ns
		SW_0 OFF to SW_2 ON		230		
		SW_1 OFF to SW_0 ON		97		
		SW_1 OFF to SW_2 ON		230		
		SW_2 OFF to SW_0 ON		96		
		SW_2 OFF to SW_1 ON		140		
C_{COM0}	COM capacitance (3) (6)	SW_{COM0} ON; SW_{COM1} and SW_{COM2} OFF		1.3		pF
C_{COM1}		SW_{COM1} ON; SW_{COM0} and SW_{COM2} OFF		1.2		
C_{COM2}		SW_{COM2} ON; SW_{COM0} and SW_{COM1} OFF		1.2		
C_{COM_OPEN}		SW_{COM0} , SW_{COM1} and SW_{COM2} OFF		1.2		
C_{FB0}	FB capacitance (5) (7)	SW_0 ON		1.9		pF
C_{FB1}		SW_1 ON		1.6		
C_{FB2}		SW_2 ON		1.5		
C_{FB0_OPEN}		SW_0 OFF		1.4		
C_{FB1_OPEN}		SW_1 OFF		1.2		
C_{FB2_OPEN}		SW_2 OFF		1.1		
R_{ON_COM0}	On resistance (8) (9)			62		Ω
R_{ON_FB0}				38		
R_{ON_COM1}				117		
R_{ON_FB1}				38		
R_{ON_COM2}				342		
R_{ON_FB2}				36		
	On resistance channel-to-channel matching (3) (4)	SW_{COM0} for Channel A and B		0.13		Ω
		SW_{FB0} for Channel A and B		0.35		
		SW_{COM1} for Channel A and B		0.45		
		SW_{FB1} for Channel A and B		0.07		
		SW_{COM2} for Channel A and B		3		
		SW_{FB2} for Channel A and B		0.1		
	Maximum data rate	All switches			10	MHz
LOGIC PIN FUNCTION (LATCH, SEL)						
	Logic low threshold	Logic low below the threshold voltage	$V_{S+} - 1.5$	$V_{S+} - 1.3$		V
	Logic high threshold	Logic high above the threshold voltage		$V_{S+} - 1.2$	$V_{S+} - 1$	V
	Bias current	$V_{PIN} = V_{S-}$ or V_{S+}		10		μA
		V_{PIN} at switching threshold		160		μA
	Setup time		100			ns
	Hold time		100			ns

- (1) All the specifications apply for both Channels A and B, unless otherwise noted.
- (2) When switching from one gain condition to another, the new gain switches are closed before opening the previous gain switches (make-before-break)
- (3) SW_{COM0} , SW_{COM1} , SW_{COM2} refer to switch on the common-mode side (COM) for the different gain options.
- (4) SW_{FB0} , SW_{FB1} , SW_{FB2} refer to switch on the feedback side (FB) for the different gain options.
- (5) SW_0 , SW_1 , SW_2 refers to the two switches needed for a given gain condition. For example, SW_0 refers to SW_{COM0} and SW_{FB0}

- (6) C_{COM0} , C_{COM1} , C_{COM2} is the capacitance at the COM pin for different gain options. It is equal to ON capacitance of closed switch + OFF capacitance of open switches.
- (7) C_{FB0} , C_{FB1} , C_{FB2} is the capacitance at the FB_X pin. It is equal to ON capacitance of the gain option selected ($SW_{COM0} + SW_{FB0}$ capacitance)
- (8) R_{ON_COM0} , R_{ON_COM1} , R_{ON_COM2} , refer to ON resistance for the COM side switch.
- (9) R_{ON_FB0} , R_{ON_FB1} , R_{ON_FB2} , refer to ON resistance for the FB side switch.

6.7 Typical Characteristics

$V_{S+} = 5\text{ V}$, $V_{S-} = 0\text{ V}$, $R_L = 200\ \Omega$, output load is referenced to midsupply, input common-mode biased at midsupply, and $T_A \approx +25^\circ\text{C}$ (unless otherwise noted)

ADVANCE INFORMATION

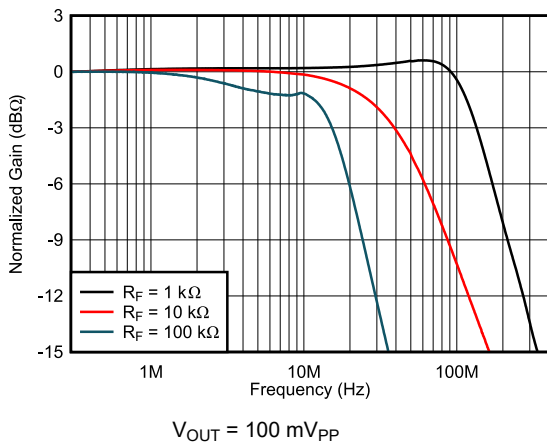


Figure 6-1. TIA Bandwidth vs Frequency

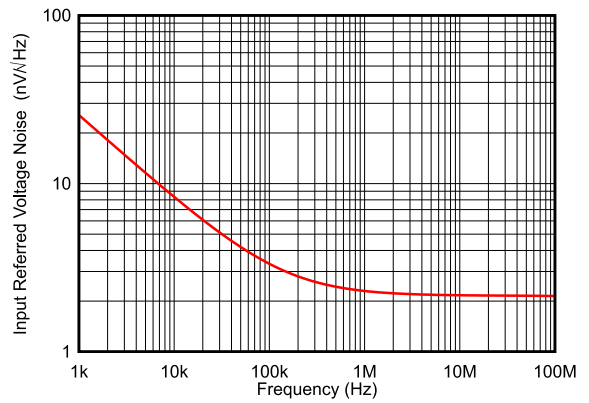


Figure 6-2. Voltage Noise Density vs Frequency

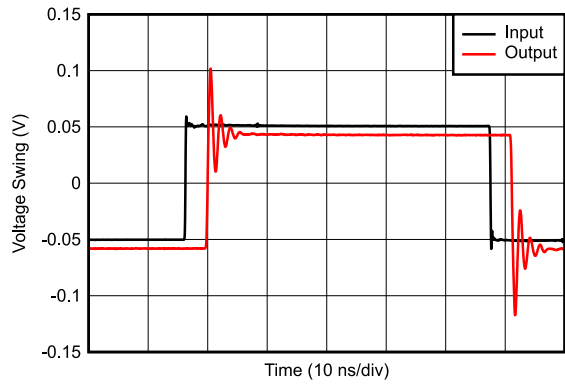


Figure 6-3. Small-Signal Transient Response

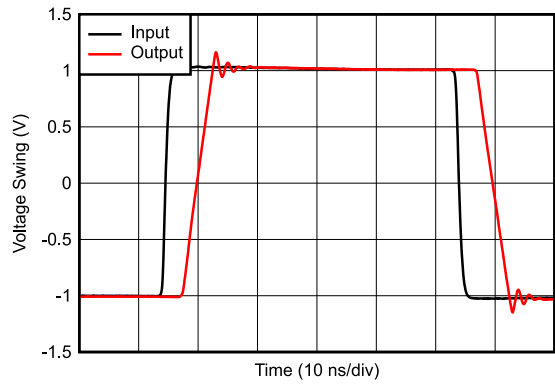


Figure 6-4. Large-Signal Transient Response

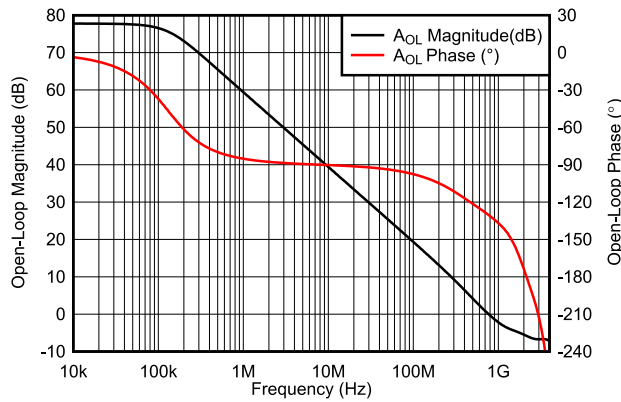


Figure 6-5. Open-Loop Magnitude and Phase vs Frequency

7 Parameter Measurement Information

The test setup configuration for OPA3S2859-EP is shown below.

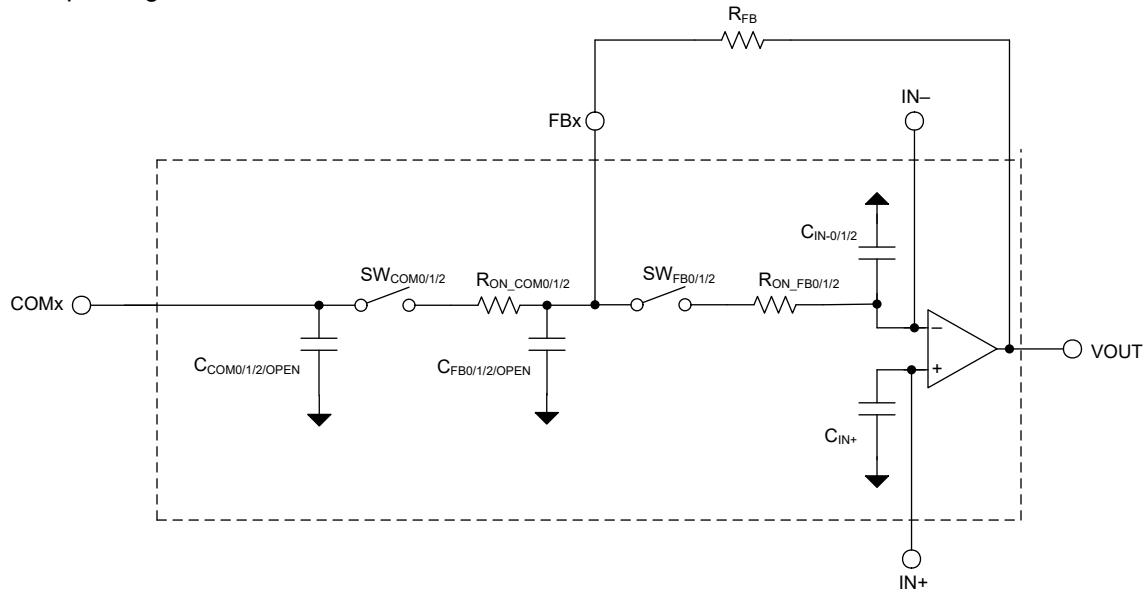


Figure 7-1. Switching Characteristics Configuration

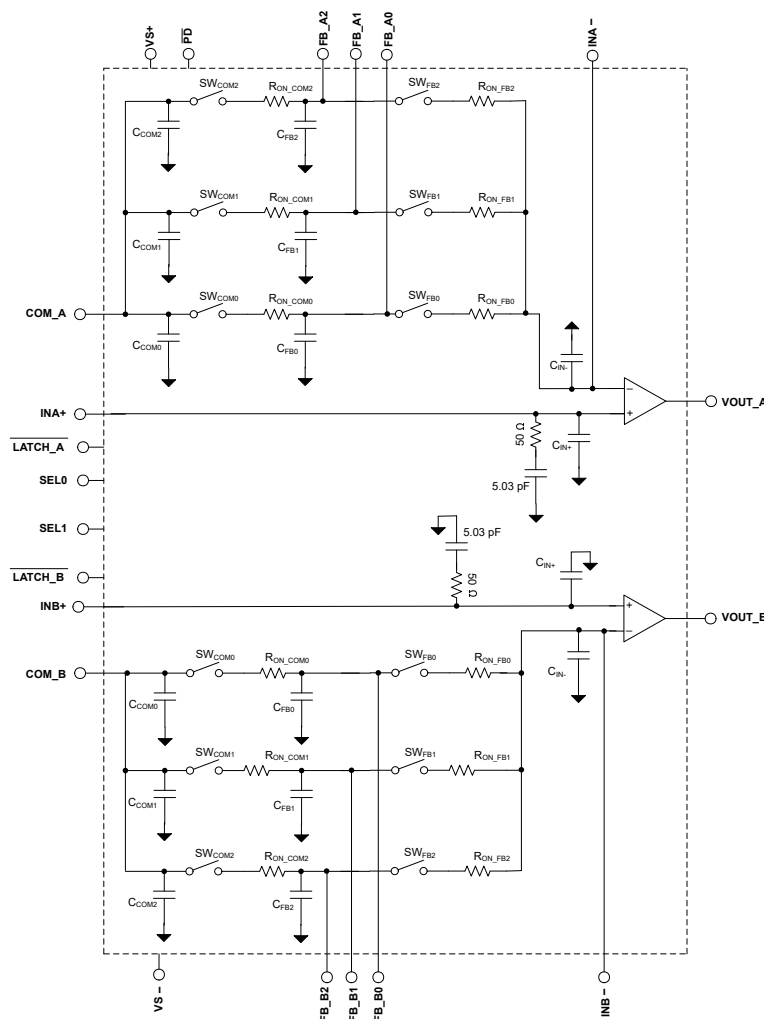
8 Detailed Description

8.1 Overview

The OPA3S2859-EP features two channels of high-speed, low noise, wide gain bandwidth amplifier with programmable gain switches to offer a compact, easy-to-use device for wideband transimpedance applications, high-speed data acquisition systems, and applications with weak signal inputs that require low-noise and high-gain front ends. Integrated switches allow for multiple gain settings on a single amplifier stage without the need for an additional multiplexer device and minimize parasitics.

The OPA3S2859-EP is offered in a 4-mm × 4-mm, 24-pin WQFN package that features multiple feedback (FB) pins for different gain options to make simple feedback network connection between the amplifier output and inverting input. The three internally switched feedback paths along with an additional parallel non-switched feedback path allows for up to four selectable gain configurations.

8.2 Functional Block Diagram



ADVANCE INFORMATION

8.3 Feature Description

8.3.1 Programmable Gain

The OPA3S2859-EP features integrated switches that can be used for implementing different gain configurations. The closed-loop bandwidth and noise of a TIA are affected by the transimpedance gain and photodiode capacitance. The OPA3S2859-EP has a higher bandwidth in its low-gain configuration for a given value of photodiode capacitance compared to the high-gain configuration. Increasing the gain of the TIA stage by a factor of X increases the output signal by a factor X , but the noise contribution from the resistor only increases by \sqrt{X} . The input-referred noise density of the low-gain configuration is therefore higher than the input-referred noise density of the high-gain configuration.

OPA3S2859-EP provides control for switching among three independently-configured external feedback networks using FB_x0, FB_x1, FB_x2 pins, and allows for up to four selectable gain configurations with an additional parallel non-switched feedback path. The internal switches minimize parasitic contributions to increase performance compared to external methods. Each switch is optimized for increasing feedback resistor values ranging from $< 1\text{ k}\Omega$ to $> 100\text{ k}\Omega$ for wide dynamic range applications. The selected switch path is controlled for both channels using a 2-wire parallel interface (SEL0 and SEL1).

In many systems it is typical that gain will switch sequentially (also known as adjacent gain switching) for example, low to medium to high or high to medium to low. When switching between adjacent gains, the switches feature make-before-break switching, when programmed to a different switch connection, the previous switch does not change to high impedance state until the new switch is closed, with a typical 100's of ns delay when both switches are closed. This feature keeps the amplifier from operating in an open-loop state when the switches are used in a switched-gain transimpedance configuration.

8.3.2 Slew Rate and Output Stage

The OPA3S2859-EP features a high slew rate of $350\text{ V}/\mu\text{s}$. The slew rate is a critical parameter in high-speed pulse applications with narrow ns pulses, such as optical time-domain reflectometry (OTDR). The high slew rate implies that the device accurately reproduces a 2-V, ns pulse edge, as seen in [Large-Signal Transient Response](#). The wide bandwidth and slew rate of the device make it an excellent amplifier for high-speed signal-chain front ends.

To achieve high slew rates and low output impedance across frequency, the output swing of the OPA3S2859-EP is limited to approximately 3 V. The OPA3S2859-EP is typically used in conjunction with high-speed pipeline ADCs and flash ADCs that have limited input ranges. Therefore, the output swing range coupled with the class-leading voltage noise specification for a CMOS amplifier maximizes the overall dynamic range of the signal chain.

8.3.3 Input and ESD Protection

The OPA3S2859-EP is fabricated on a low-voltage, high-speed, BiCMOS process. The internal, junction breakdown voltages are low for these small geometry devices, and as a result, all device pins are protected with internal ESD protection diodes to the power supplies. There are two antiparallel diodes between the inputs of the amplifier that clamp the inputs during an overrange or fault condition.

8.4 Device Functional Modes

8.4.1 Split-Supply and Single-Supply Operation

The OPA3S2859-EP can be configured with single-sided supplies or split-supplies. Split-supply operation using balanced supplies with the input common-mode set to ground eases lab testing because most signal generators, network analyzers, spectrum analyzers, and other lab equipment typically reference inputs and outputs to ground. In split-supply operation, the thermal pad must be connected to the negative supply.

Newer systems use a single power supply to improve efficiency and reduce the cost of the extra power supply. The OPA3S2859-EP can be used with a single positive supply (negative supply at ground) with no change in performance if the input common-mode and output swing are biased within the linear operation of the device. In single-supply operation, level shift the DC input and output reference voltages by half the difference between the power supply rails. This configuration maintains the input common-mode and output load reference at midsupply. To eliminate gain errors, the source driving the reference input common-mode voltage must have low output impedance across the frequency range of interest. In this case, the thermal pad must be connected to ground.

8.4.2 Power-Down Mode

The OPA3S2859-EP features a power-down mode to conserve power. Connecting the $\overline{\text{PD}}$ pin low disables the amplifier thereby reducing the quiescent current and places the output in a high-impedance state.

$\overline{\text{PD}}$ pin has an internal pull up resistor, if the pin is left floating then the device defaults to an ON state. The $\overline{\text{PD}}$ disable and enable threshold voltages are with reference to the positive supply, as shown in the Electrical Characteristics section. If the amplifier is configured with the positive supply at 5 V and the negative supply at ground, then the disable and enable threshold voltages are 3.5 V and 4 V, respectively. If the amplifier is configured with ± 2.5 V supplies, then the threshold voltages are at 1 V and 1.5 V.

8.4.3 Gain Select Mode (SEL)

The OPA3S2859-EP features two pins SEL0 and SEL1 to choose between three different internal switch networks and an external option. The SELx disable and enable threshold voltages are with reference to the positive supply as shown in the Electrical Characteristics table. Note: while the SELx logic will select the same switch configuration for channel A and B, the external components (feedback network) of channels A and B do not have to be exactly the same.

When switching between different gain settings (feedback networks), the device has a transition time of only a few 100 ns as shown in the Switching Characteristics table. In many systems, it is typical that gain will be stepped sequentially (for example, low to medium to high or high to medium to low). The SELx logic assignment ensures that switching gains up or down involve only one input-pin transition, reducing the probability of unintended false codes during logic settling.

1. Low Gain (SEL1 = Low, SEL0 = High)

The feedback networks connected to pins FB_A0 and FB_B0 are selected. Analog response is optimized for R_F values on the order of 1 k Ω , though in practice a wide range of R_F values can be used (<10 k Ω).

2. Mid Gain (SEL1 = Low, SEL0 = Low)

The feedback networks connected to pins FB_A1 and FB_B1 are selected. Analog response is optimized for R_F values on the order of 10 k Ω , though in practice a wide range of R_F values can be used (>10 k Ω , <100 k Ω).

3. High Gain (SEL1 = High, SEL0 = Low)

The feedback networks connected to pins FB_A2 and FB_B2 are selected. Analog response is optimized for R_F values on the order of 100 k Ω , though in practice a wide range of R_F values can be used (>100 k Ω).

4. External Gain (SEL1 = High, SEL0 = High)

Any feedback networks connected to pins FB_Ax and FB_Bx are un-selected. This mode can be used to configure OPA3S2859-EP as a standard op-amp, with the feedback network connected to the INA- or INB-pin.

8.4.4 Latch Mode

OPA3S2859-EP features $\overline{\text{LTCH_A}}$ and $\overline{\text{LTCH_B}}$ pins which independently latch the gain configuration for Channel A and Channel B, respectively. If the latch control inputs are connected to logic high or floating, then the chosen feedback selection (through SEL0, SEL1 pins) applies to A and B analog channels immediately, this is also called transparent mode. If the latch control inputs are logic low, then changing the feedback selection (through SEL0 and SEL1 pins) does not affect the gain configuration of the respective amplifier channel.

By using the latch control input for each channel, the feedback selection can be controlled separately from the common SEL1 and SEL0 pins. For example, the gain setting can be updated only for channel A, by latching the gain setting for channel B by setting $\overline{\text{LTCH_B}}$ pin to logic low. The latch control inputs can also provide benefits in some cases where channel A and B need to have the same configuration. For example, in transparent mode, when switching between different gain settings any timing skew from SEL1 and SEL0 may result in unintended switch logic configurations for a short-duration resulting in transient output glitch. These intermediate glitch states can be minimized by holding $\overline{\text{LTCH_x}}$ pin low until the new selection value at SEL pins has settled.

This feature is also useful in larger systems with multiple OPA3S2859-EP devices, the gain path can be set using common SEL0 and SEL1 signals for all the devices and latch pins can be used to control the gain independently for each amplifier channel.

9 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Application Information

The OPA3S2859-EP offers a unique combination of dual channel, wide bandwidth low noise amplifiers with integrated programmable gain switches. This combination makes this amplifier excellent choice for photodiode transimpedance amplifier applications with variable gain needs.

9.2 Typical Application

Figure 9-1 shows the circuit used to measure transimpedance bandwidth of the OPA3S2859-EP with different feedback network setting options. This configuration demonstrates the use case when the photodiode's anode is tied to the amplifier input and its cathode is tied to a positive voltage.

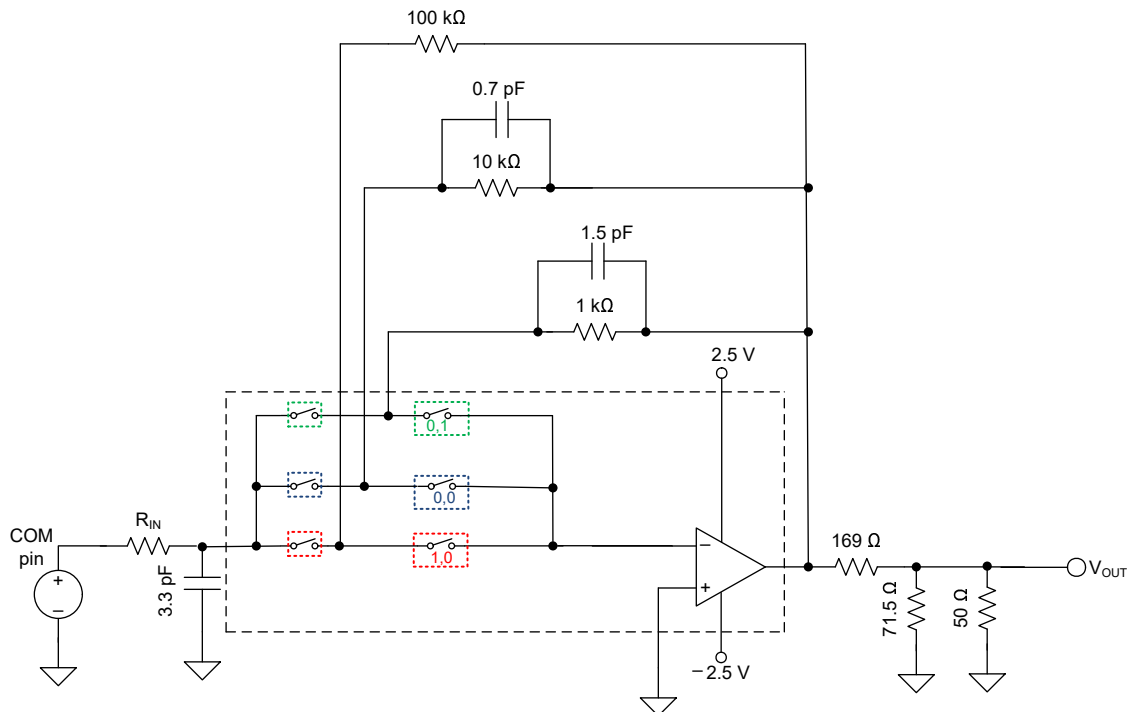


Figure 9-1. OPA3S2859-EP Test Circuit

9.2.1 Design Requirements

The objective is to design a variable gain, low noise, wideband optical front-end transimpedance amplifier. The design requirements are:

- Amplifier supply voltage: ± 2.5 V
- Transimpedance gain: 1 k Ω , 10 k Ω , 100 k Ω
- Photodiode capacitance: $C_{APD} = 3.3$ pF (additional estimated PCB capacitance = 0.7 pF)
- Target bandwidth: 130 MHz, 40 MHz, 14 MHz

9.2.2 Detailed Design Procedure

The OPA3S2859-EP meets the growing demand for wideband, low-noise photodiode amplifiers. The closed-loop bandwidth of a transimpedance amplifier is a function of the following:

1. The total input capacitance (C_{IN}). This total includes the photodiode capacitance, the input capacitance of the amplifier (common-mode and differential capacitance) and any stray capacitance from the PCB.
2. The op amp gain bandwidth product (GBWP).
3. The transimpedance gain (R_F).

Figure 9-1 shows the OPA3S2859-EP configured as programmable gain TIA using different feedback paths through switch network. The feedback resistance (R_F) and the input capacitance (C_{IN}) form a zero in the noise gain that results in instability if left unchecked. To counteract the effect of the zero, a pole is inserted into the noise gain transfer function by adding the feedback capacitor (C_F). The [Transimpedance Considerations for High-Speed Amplifiers Application Report](#) discusses theories and equations that show how to compensate a transimpedance amplifier for a particular transimpedance gain and input capacitance. The bandwidth and compensation equations from the application report are available in an Excel® calculator. [What You Need To Know About Transimpedance Amplifiers – Part 1](#) provides a link to the calculator.

The equations and calculators in the referenced application report and blog posts are used to model the bandwidth (f_{-3dB}) and noise performance of the OPA3S2859-EP configured as a TIA. For this setup, to emulate an ideal current source, choose R_{IN} value to be 1 to 10x greater than R_F such that the low frequency noise gain closer to 1 V/V to 2 V/V ($R_F = 1\text{ k}\Omega, 10\text{ k}\Omega, 100\text{ k}\Omega, R_{IN} = 10\text{ k}\Omega, 100\text{ k}\Omega, 100\text{ k}\Omega$;respectively). The resultant performance is shown in Figure 9-2. To maximize bandwidth, make sure to reduce any stray parasitic capacitance from the PCB. Increasing R_F results in lower bandwidth. To maximize the signal-to-noise ratio (SNR) in an optical front-end system, maximize the gain in the TIA stage. Increasing R_F by a factor of X increases the signal level by X, but only increases the resistor noise contribution by \sqrt{X} , thereby improving SNR.

9.2.3 Application Curves

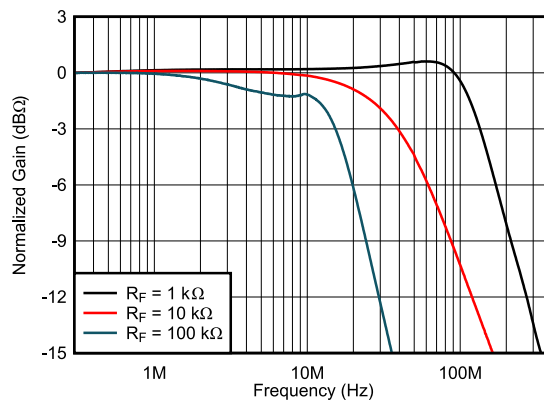


Figure 9-2. Bandwidth vs Frequency

10 Power Supply Recommendations

The OPA3S2859-EP operates on supplies from 3.3 V to 5.25 V. The device operates on single-sided supplies, split and balanced bipolar supplies, and unbalanced bipolar supplies. Because the OPA3S2859-EP does not feature rail-to-rail inputs or outputs, the input common-mode and output swing ranges are limited at 3.3-V supplies.

11 Layout

11.1 Layout Guidelines

Achieving optimum performance with a high-frequency amplifier, such as the OPA3S2859-EP, requires careful attention to board layout parasitics and external component types. Recommendations that optimize performance include the following:

- **Reduce capacitive coupling between feedback traces.** Trace-to-trace capacitance between the three feedback connection traces can cause the traces to couple together at high frequency and effect the gain of the device. Particularly for high gain feedback configurations, capacitive coupling to feedback paths with lower gain can significantly reduce the bandwidth if not properly isolated. For example, in a circuit configuration with 100k, 10k and 1k feedback elements, the 100k gain path can see over 66% reduction in bandwidth when using an non-optimized feedback layout. To properly isolate the feedback traces it is important to space the traces out and pour ground plane between the traces to isolate their capacitance; additional trace length, however, does add further inductance and capacitance to the traces which can also effect performance. Therefore, it is important to balance the feedback area and trace length to best minimize the major parasitic effect. A good starting point is to use a design similar to the evaluation module with a feedback area of approximately 6 mm × 6 mm. This can then be adjusted depending on circuit limitations and needs.
- **Minimize parasitic capacitance from the signal I/O pins to ac ground.** Parasitic capacitance on the output pins can cause instability where as parasitic capacitance on the input pin reduces the amplifier bandwidth. To reduce unwanted capacitance, cut out the power and ground traces under the signal input pins, output pins, and exterior feedback trace when possible. A small value isolation resistor between the DUT output and feedback network can also help reduce the parasitic loading caused by the feedback trace on the output. Otherwise, ground and power planes must be unbroken elsewhere on the board.
- **Minimize the distance from the power-supply pins to high-frequency bypass capacitors.** Use high-quality, 100-pF to 0.1- μ F, C0G and NPO-type decoupling capacitors with voltage ratings at least three times greater than the amplifiers maximum power supplies. Place the smallest value capacitors on the same side as the DUT. If space constraints force the larger value bypass capacitors to be placed on the opposite side of the PCB, use multiple vias on the supply and ground side of the capacitors. This configuration makes sure that there is a low-impedance path to the amplifiers power-supply pins across the amplifiers gain bandwidth specification. Avoid narrow power and ground traces to minimize inductance between the pins and the decoupling capacitors. Larger (2.2- μ F to 6.8- μ F) decoupling capacitors that are effective at lower frequency must be used on the supply pins. Place these decoupling capacitors further from the device. Share the decoupling capacitors among several devices in the same area of the printed circuit board (PCB).

11.2 Layout Examples

Figure 11-1 shows a typical layout around the OPA3S2859-EP based on the evaluation module. The smallest decoupling capacitors were placed as close as possible to the DUT with wide metal area to minimize inductance. Special attention was placed on the feedback network layout to optimize the design for a typical application using 1k Ω , 10 k Ω , and 100 k Ω feedback resistors. Please see Figure 11-2 for more details. The black colored areas under the input and feedback traces show the voids cut in the ground plane underneath the traces to minimize capacitance to ground as much as possible.

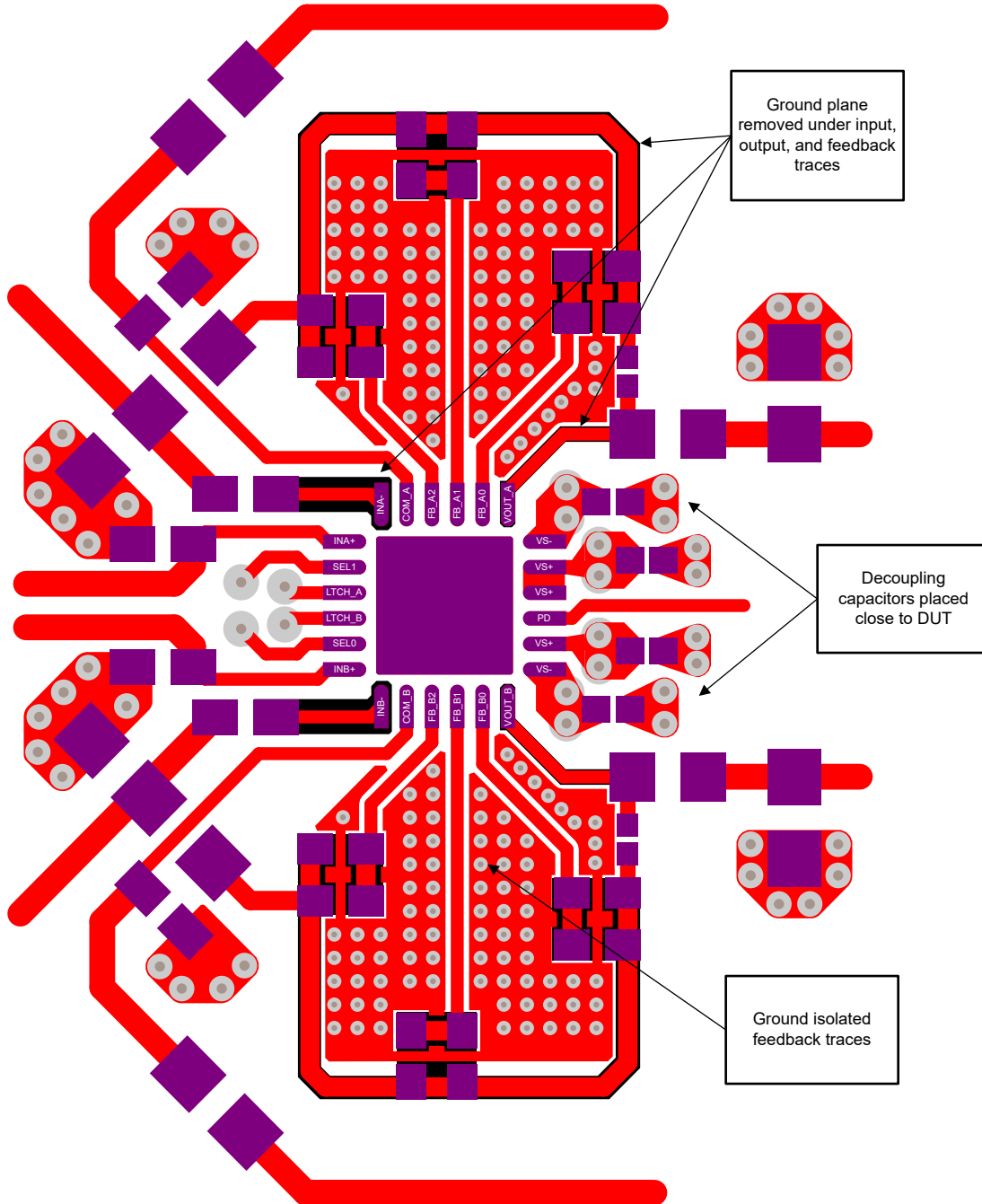


Figure 11-1. General Layout Example

Figure 11-2 shows an example of a feedback network from the evaluation module optimized to reduce the capacitive coupling between the feedback and output traces. Ground plane is poured between each of the feedback traces and component footprints as much as possible for the best isolation. A small isolation resistor (RISO) is connected between the output and feedback trace to help isolate the trace capacitance from being directly connected to the DUT output. Additionally, the ground plane is removed from under the feedback trace to further reduce the parasitic capacitance to ground created by the additional trace length required for the feedback network.

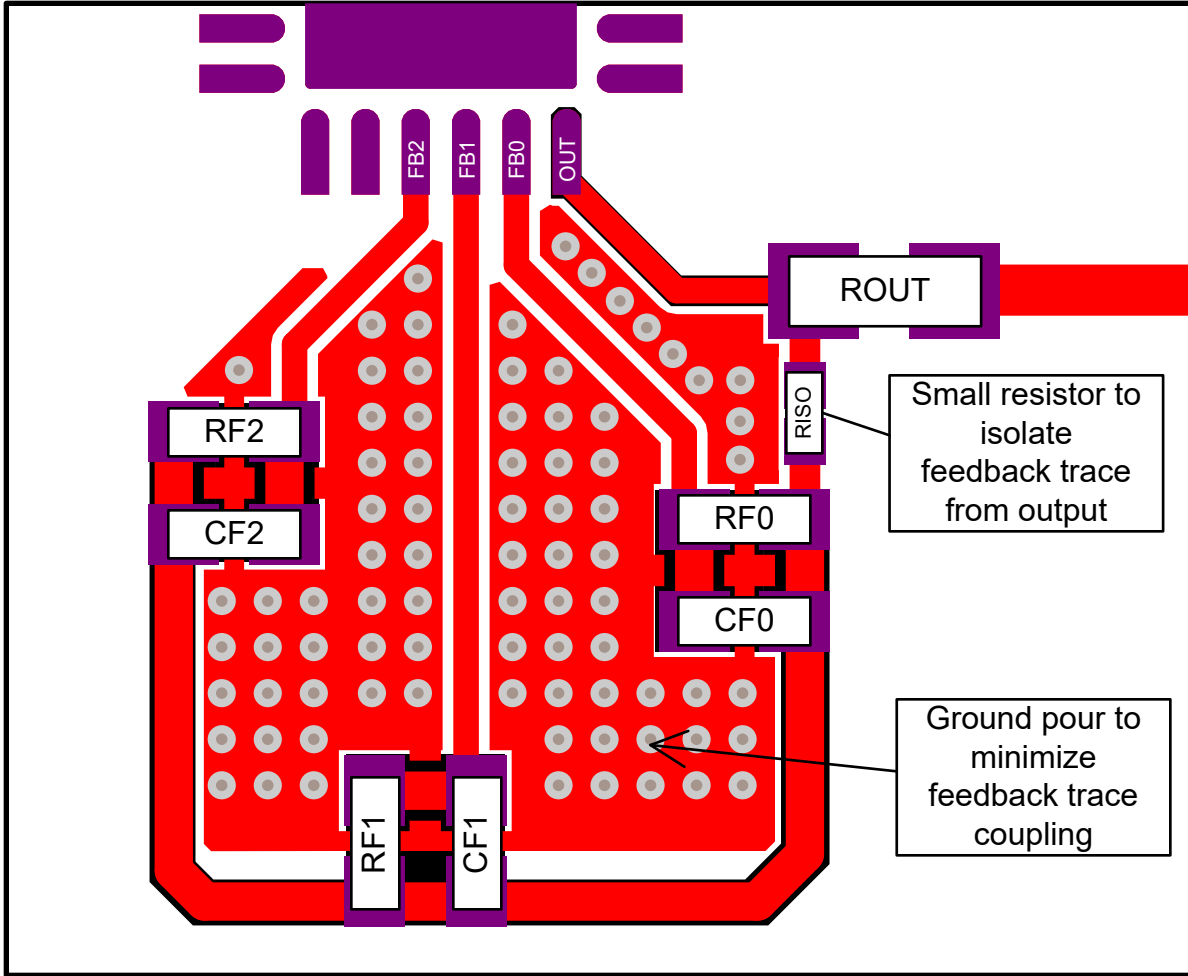


Figure 11-2. Feedback Network Layout Reccomendations

12 Device and Documentation Support

12.1 Device Support

12.1.1 Development Support

- Texas Instruments, [Optical Front-End System Reference Design design guide](#)
- Texas Instruments, [LIDAR-Pulsed Time-of-Flight Reference Design Using High-Speed Data Converters design guide](#)
- Texas Instruments, [LIDAR Pulsed Time of Flight Reference Design design guide](#)

12.2 Documentation Support

12.2.1 Related Documentation

See the following for related documentation:

- Texas Instruments, [OPA3S2859-EP Evaluation Module user's guide](#)
- Texas Instruments, [Transimpedance Considerations for High-Speed Amplifiers application report](#)
- Texas Instruments, [What You Need To Know About Transimpedance Amplifiers – Part 1 blog](#)
- Texas Instruments, [What You Need To Know About Transimpedance Amplifiers – Part 2 blog](#)
- Texas Instruments, [Training Video: How to Design Transimpedance Amplifier Circuits](#)
- Texas Instruments, [Training Video: High-Speed Transimpedance Amplifier Design Flow](#)
- Texas Instruments, [Training Video: How to Convert a TINA-TI Model into a Generic SPICE Model](#)

12.3 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on [ti.com](#). Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

12.4 Support Resources

[TI E2E™ support forums](#) are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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12.5 Trademarks

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12.6 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

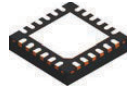
ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

12.7 Glossary

[TI Glossary](#) This glossary lists and explains terms, acronyms, and definitions.

13 Mechanical, Packaging, and Orderable Information

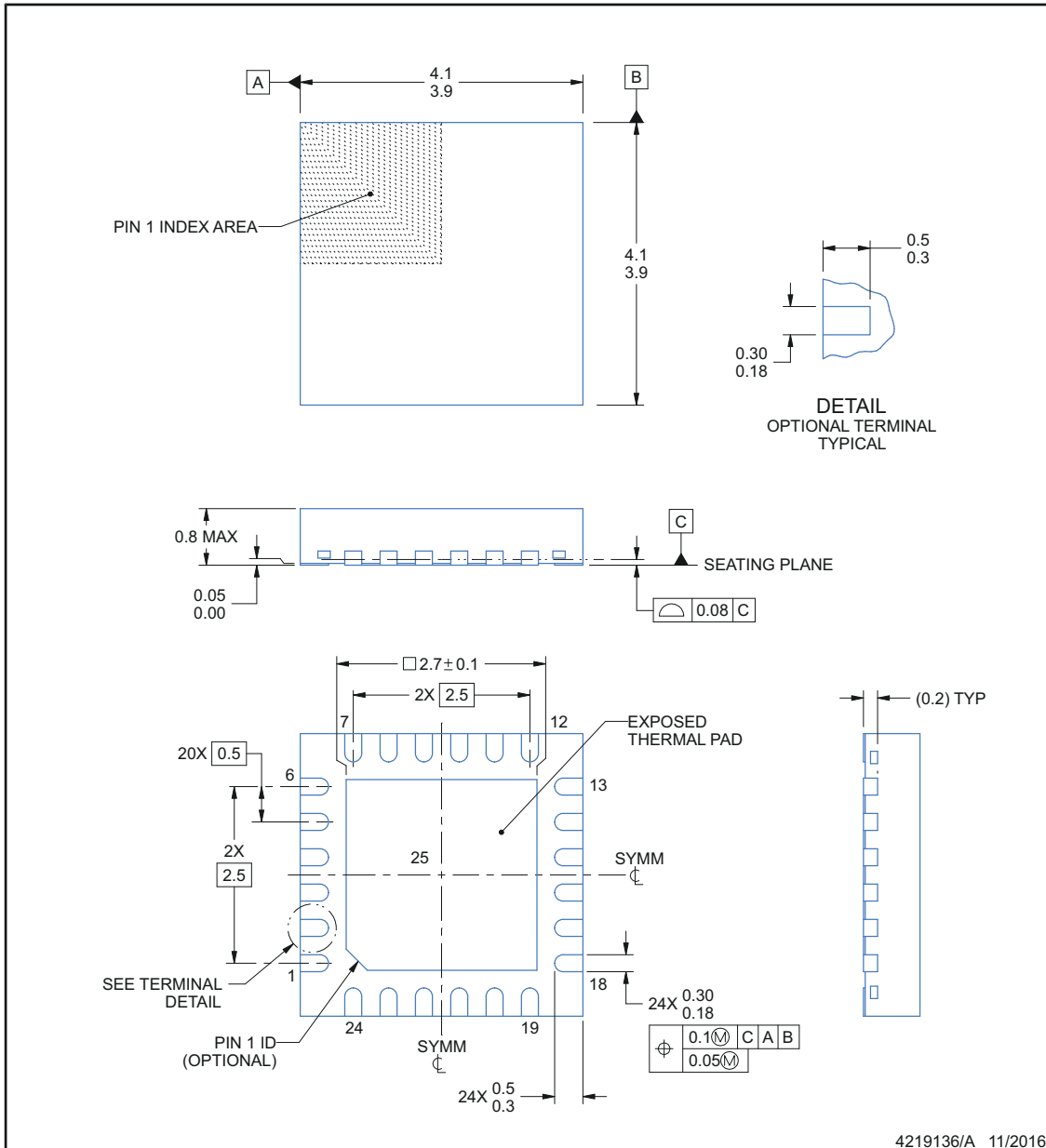
The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



RTW0024H

PACKAGE OUTLINE
WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



4219136/A 11/2016

NOTES:

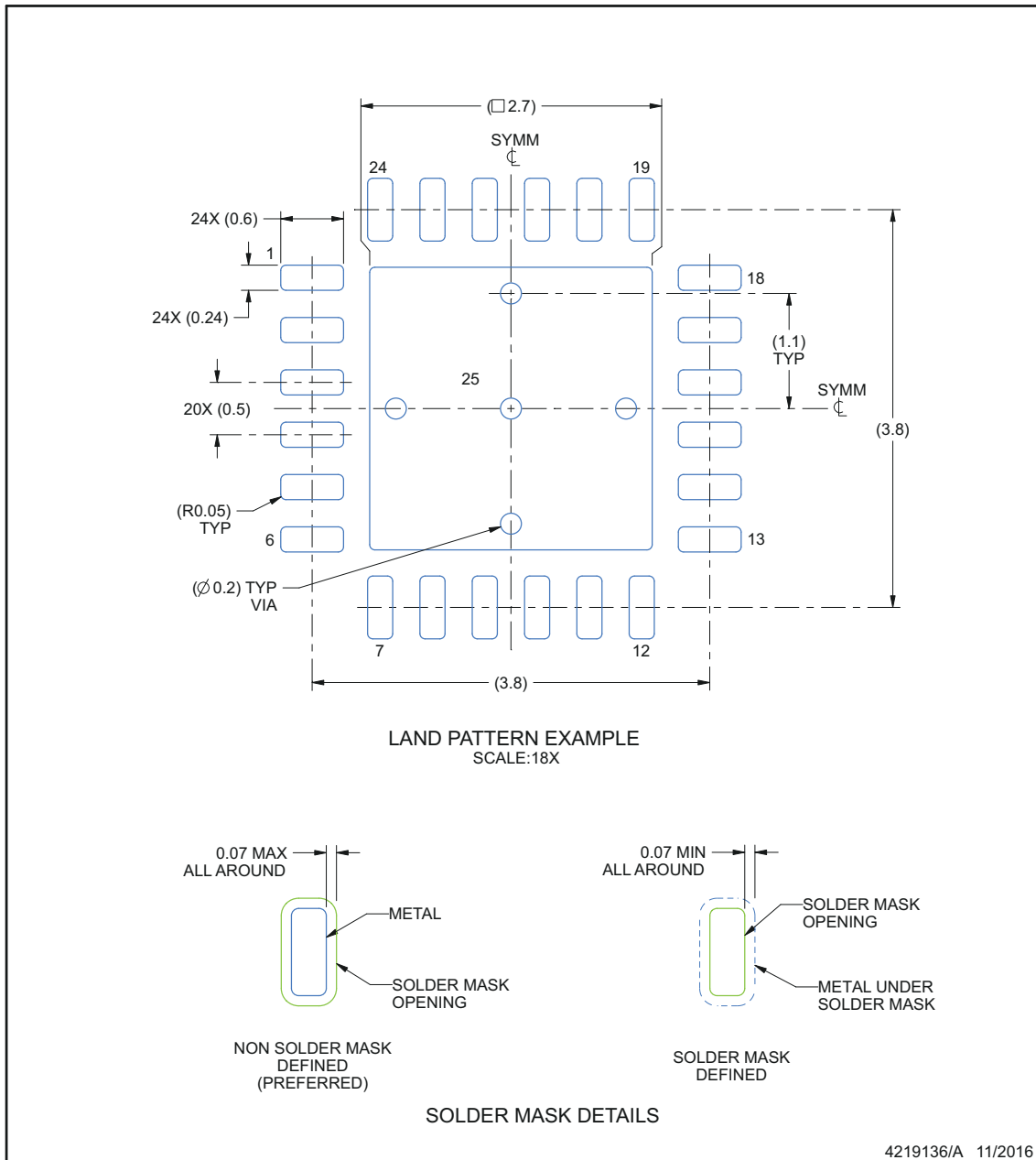
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.
4. Reference JEDEC registration MO-220.

EXAMPLE BOARD LAYOUT

RTW0024H

WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

5. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
6. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.

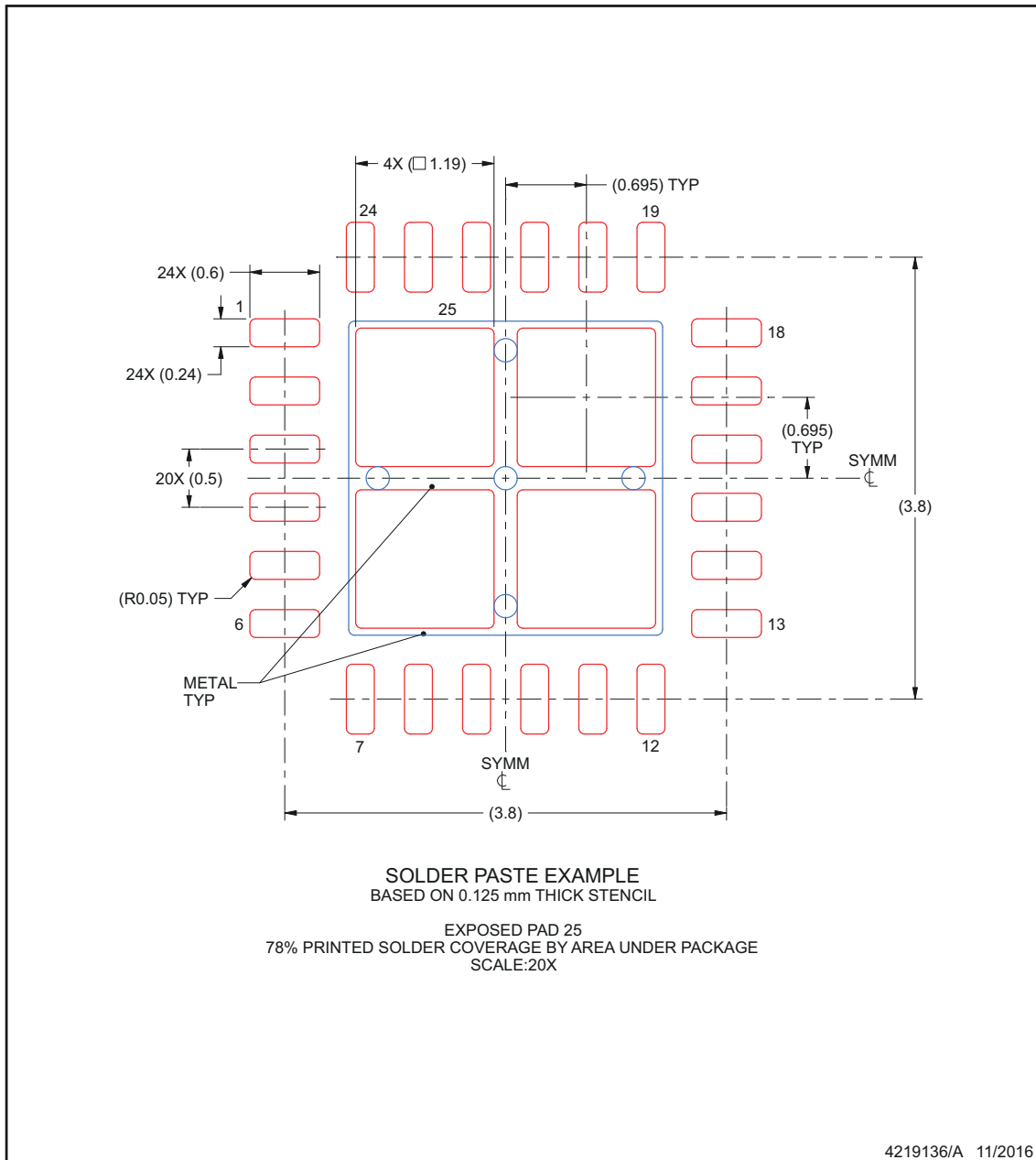
EXAMPLE STENCIL DESIGN

RTW0024H

WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD

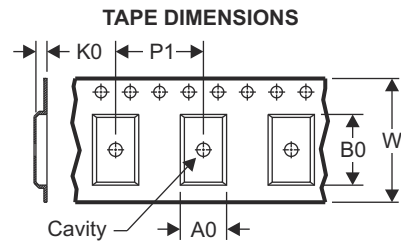
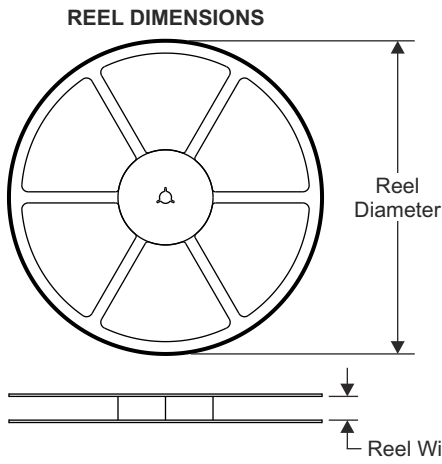
ADVANCE INFORMATION



NOTES: (continued)

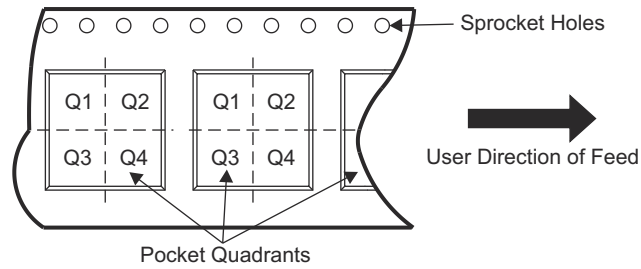
7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

13.1 Tape and Reel Information



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



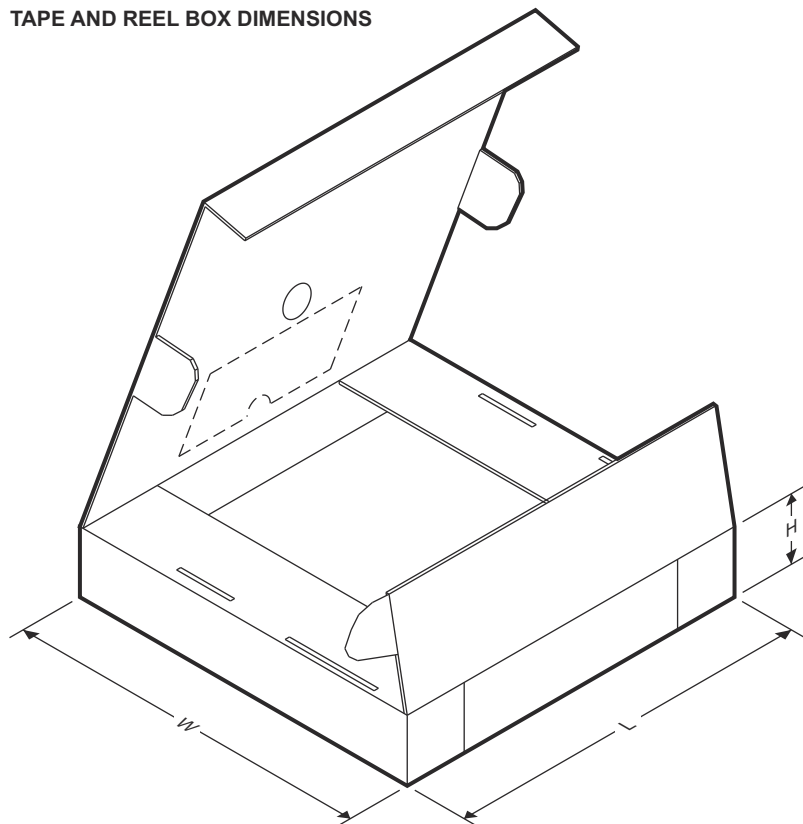
Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
XOPA3S2859MRTWREP	WQFN	RTW	24	3000	330	12.4	4.25	4.25	1.15	8	12	Q2

ADVANCE INFORMATION

OPA3S2859-EP

SBOSA61A – OCTOBER 2019 – REVISED APRIL 2021


TAPE AND REEL BOX DIMENSIONS



ADVANCE INFORMATION

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
XOPA3S2859MRTWREP	WQFN	RTW	24	3000	367	367	35

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
XOPA3S2859MRTWREP	ACTIVE	WQFN	RTW	24	3000	Non-RoHS & Non-Green	Call TI	Call TI	-55 to 125		

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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